



Test Report

MERITEK ELECTRONICS CORPORATION
11824 HAMDEN PLACE
SANTA FE SPRINGS, CA 90670
USA

Report No. : CE/2004/80790B
Date : 2004/08/12
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The following merchandise was (were) submitted and identified by the client as :


Type of Product : METAL FILM RESISTORS
Sample Received : 2004/08/06
Testing Date : 2004/08/06 TO 2004/08/12

Test Result

PART NAME NO.1 : PLEASE REFER TO THE SAMPLE CARD(S).(MIX ALL PARTS)

Test Item (s):	Unit	Method	MDL	Result				
				No.1				
Chromium VI (Cr+6)	ppm	As per US EPA 7196A and US EPA 3060A.	2	N.D.				
Cadmium (Cd)	ppm	ICP-AES after as per EN 1122, method B:2001 or other acid digestion.	2	N.D.				
Mercury (Hg)	ppm	ICP-AES after as per US EPA 3052 or other acid digestion.	2	N.D.				
Lead (Pb)	ppm	ICP-AES after as per US EPA 3050B or other acid digestion.	2	N.D.				

NOTE : (1) N.D. = Not detected (<MDL)
(2) ppm = mg/kg
(3) MDL = Method Detection Limit


Daniel Yeh, M.R. / Operation Manager
Signed for and on behalf of
SGS TAIWAN LTD.

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